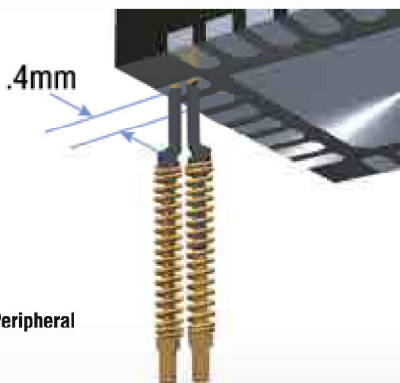


Z - Kelvin

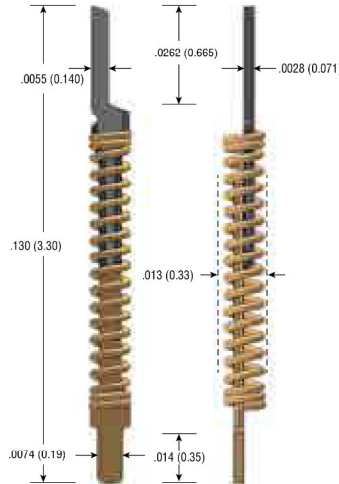
0.40 mm

Z-KELVIN

ECT's ZIP® Kelvin .4mm is ideal for voltage sensitive tests on array or peripheral devices requiring milliohm resistance measurements as well as high-power test applications.



Z-040KHJ



Mechanical

Pitch:	.016 (0.40)
Recommended Travel:	.025 (0.64)
Full Travel:	.028 (0.71)
Test Height:	.105 (2.67)
Mechanical Life*:	500,000 cycles
Operating Temperature:	-55°C to +155°C
Spring Force in oz. (grams):	1.20 (34)


Electrical (Static Conditions)

Current Rating DC:	2.2 amps
Average DC Probe Resistance** :	<70 mOhms
Self Inductance (Ls):	0.90 nH
Capacitance (Cc):	0.03 pF
Bandwidth @ -1dB:	9.1 GHz

Materials and Finishes

Plunger DUT:	HyperCore™
Plunger HIB:	BeCu with proprietary plating
Spring:	Stainless Steel, Gold plated

Tip Style - DUT

K			
			

Tip Style - HIB

J			
			



Dimensions in inches (millimeters). Specifications subject to change without notice.
 Consult factory for other temperature requirements, and applications below -40°C.
 Stocking Disclaimer: Stocking levels for part numbers listed in this catalog are subject to change.
 Availability is based on current levels of usage and demand.

* Life specifications are based on lab results but are dependent on cleaning frequency and the specific customer application, including DUT materials, handler kit, maintenance, etc.
 ** Contact resistance will increase over time due to solder build-up and wear

